Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

NAKAZAWA ET AL.

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Examiner

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David Q. Nguyen

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Art Unit

SEARCHED					
Class	Subclass	Date	Examiner		
455	423-425	9/12/2006	DN		
455	63.1	9/12/2006	DN		
455	63.2	9/12/2006	DN		
455	67.11	9/12/2006	DN		
455	67.13	9/12/2006	DN		
455	67.7	9/12/2006	DN		
455	560	9/12/2006	DN		
455	561	9/12/2006	DN		
370	278	9/12/2006	DN		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
PGPUB text search-See interference search printout		9/12/2006	DN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East-See Search History Printout	9/12/2006	DN		
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